



YOUSHANG SEMICONDUCTOR

**设计研发新型功率器件**

**各类小信号开关**

**中低压及高压大电流等场效应管**

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企业微信二维码



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## Product Summary

$BV_{DSS}$	$R_{DS(ON)}$	$I_D$ $T_C = +25^\circ C$
40V	5.5m $\Omega$ @ $V_{GS} = 10V$	79A

## Features

- Rated to +175°C – Ideal for High Ambient Temperature Environments
- 100% Unclamped Inductive Switching (UIS) Test in Production – Ensures More Reliable and Robust End Application
- High Conversion Efficiency
- Low  $R_{DS(ON)}$  – Minimizes On-State Losses
- Low Input Capacitance
- Fast Switching Speed
- Wettable Flank for Improved Optical Inspection

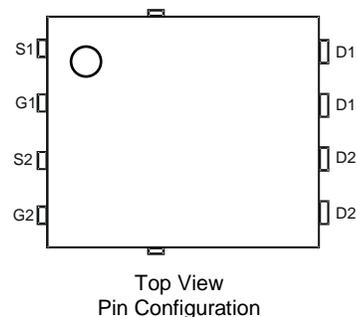
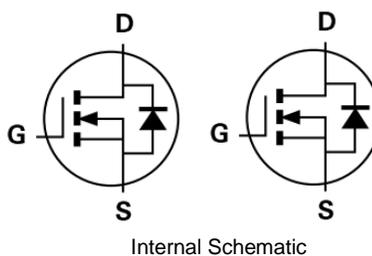
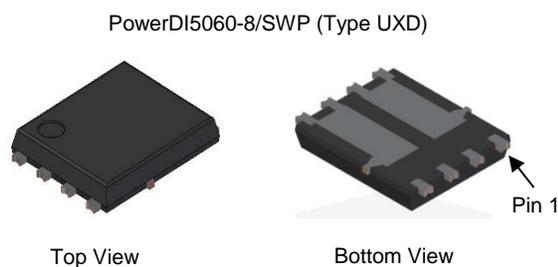
## Description and Applications

This MOSFET is designed to meet the stringent requirements of automotive applications. It is qualified to AEC-Q101, supported by a PPAP, and is ideal for use in:

- Wireless charging
- DC-DC converters
- Power management

## Mechanical Data

- Package: PowerDI<sup>®</sup>5060-8
- Package Material: Molded Plastic, “Green” Molding Compound. UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminal Finish – Matte Tin Annealed over Copper Leadframe; Solderable per MIL-STD-202, Method 208 (B3)
- Weight: 0.097 grams (Approximate)



### Maximum Ratings (@ $T_A = +25^\circ\text{C}$ , unless otherwise specified.)

Characteristic	Symbol	Value	Unit	
Drain-Source Voltage	$V_{DSS}$	40	V	
Gate-Source Voltage	$V_{GSS}$	$\pm 20$	V	
Continuous Drain Current, $V_{GS} = 10\text{V}$ (Note 5)	$I_D$	$T_C = +25^\circ\text{C}$	79	A
		$T_C = +100^\circ\text{C}$	55	A
Pulsed Drain Current (10 $\mu\text{s}$ Pulse, Duty Cycle = 1%)	$I_{DM}$	316	A	
Maximum Continuous Body Diode Forward Current (Note 5)	$I_S$	79	A	
Pulsed Body Diode Forward Current (10 $\mu\text{s}$ Pulse, Duty Cycle = 1%)	$I_{SM}$	316	A	
Avalanche Current $L = 0.1\text{mH}$	$I_{AS}$	20.3	A	
Avalanche Energy $L = 0.1\text{mH}$	$E_{AS}$	20.6	mJ	

### Thermal Characteristics

Characteristic	Symbol	Value	Unit
Total Power Dissipation (Note 6)	$P_D$	3.3	W
Thermal Resistance, Junction to Ambient (Note 6)	$R_{\theta JA}$	45	$^\circ\text{C}/\text{W}$
Total Power Dissipation (Note 5)	$P_D$	60	W
Thermal Resistance, Junction to Case (Note 5)	$R_{\theta JC}$	2.5	$^\circ\text{C}/\text{W}$
Operating and Storage Temperature Range	$T_J, T_{STG}$	-55 to +175	$^\circ\text{C}$

Notes: 5. Thermal resistance from junction to soldering point (on the exposed drain pad).  
 6. Device mounted on FR-4 substrate PC board, 2oz. copper, with thermal bias to bottom layer 1inch square copper plate.

**Electrical Characteristics** (@  $T_A = +25^\circ\text{C}$ , unless otherwise specified.)

Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
<b>OFF CHARACTERISTICS (Note 7)</b>						
Drain-Source Breakdown Voltage	$BV_{DSS}$	40	—	—	V	$V_{GS} = 0V, I_D = 250\mu A$
Zero Gate Voltage Drain Current	$I_{DSS}$	—	—	1	$\mu A$	$V_{DS} = 32V, V_{GS} = 0V$
Gate-Source Leakage	$I_{GSS}$	—	—	$\pm 100$	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$
<b>ON CHARACTERISTICS (Note 7)</b>						
Gate Threshold Voltage	$V_{GS(th)}$	2.0	—	3.5	V	$V_{DS} = V_{GS}, I_D = 250\mu A$
Static Drain-Source On-Resistance	$R_{DS(ON)}$	—	4.3	5.5	m $\Omega$	$V_{GS} = 10V, I_D = 25A$
Diode Forward Voltage	$V_{SD}$	—	0.9	1.2	V	$V_{GS} = 0V, I_S = 25A$
<b>DYNAMIC CHARACTERISTICS (Note 8)</b>						
Input Capacitance	$C_{iss}$	—	1083	—	pF	$V_{DS} = 20V, V_{GS} = 0V$ $f = 1MHz$
Output Capacitance	$C_{oss}$	—	621	—		
Reverse Transfer Capacitance	$C_{rss}$	—	21	—		
Gate Resistance	$R_G$	—	1.5	—	$\Omega$	$V_{DS} = 0V, V_{GS} = 0V, f = 1MHz$
Total Gate Charge	$Q_g$	—	13.2	—	nC	$V_{DS} = 20V, I_D = 25A, V_{GS} = 10V$
Gate-Source Charge	$Q_{gs}$	—	4.2	—		
Gate-Drain Charge	$Q_{gd}$	—	0.9	—		
Turn-On Delay Time	$t_{D(ON)}$	—	5.4	—	ns	$V_{GS} = 10V, V_{DD} = 20V$ $R_G = 3.5\Omega, I_D = 25A$
Turn-On Rise Time	$t_R$	—	2.5	—		
Turn-Off Delay Time	$t_{D(OFF)}$	—	16.1	—		
Turn-Off Fall Time	$t_F$	—	4.5	—		
Reverse Recovery Time	$t_{RR}$	—	61.3	—	ns	$I_F = 25A, di/dt = 100A/\mu s$
Reverse Recovery Charge	$Q_{RR}$	—	52.1	—	nC	

Notes: 7. Short duration pulse test used to minimize self-heating effect.  
 8. Guaranteed by design. Not subject to product testing.

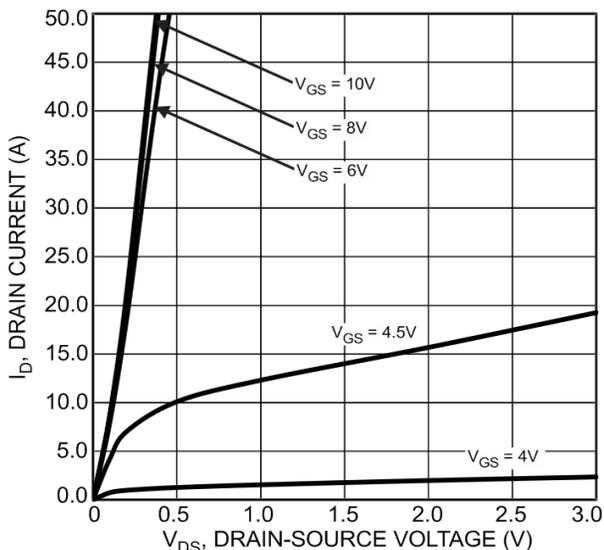


Fig. 1 Typical Output Characteristic

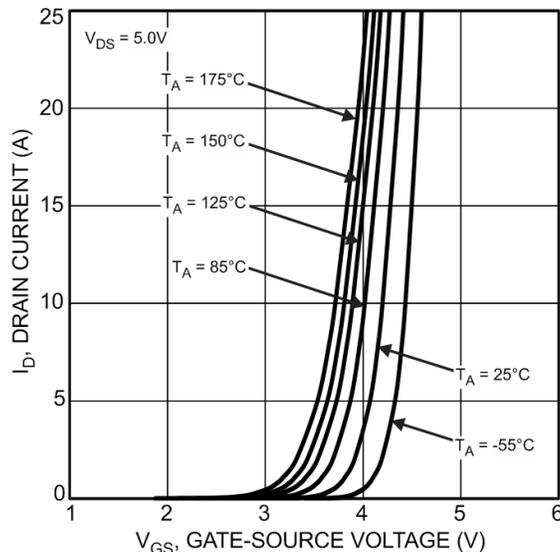


Fig. 2 Typical Transfer Characteristics

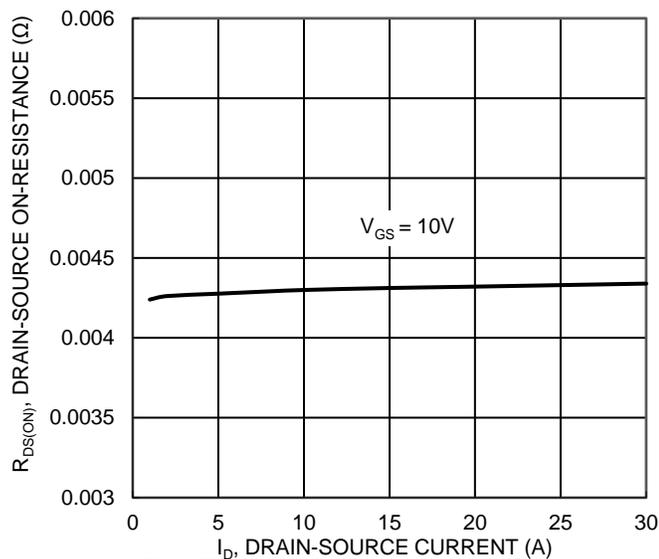


Fig. 3 Typical On-Resistance vs. Drain Current and Gate Voltage

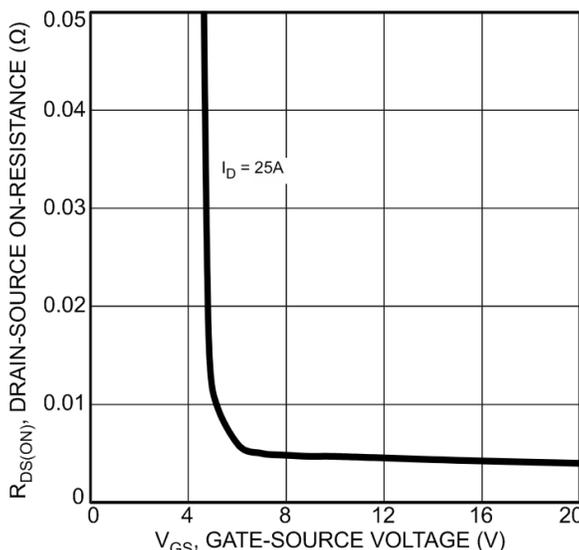


Fig. 4 Typical Drain-Source On-Resistance vs. Gate-Source Voltage

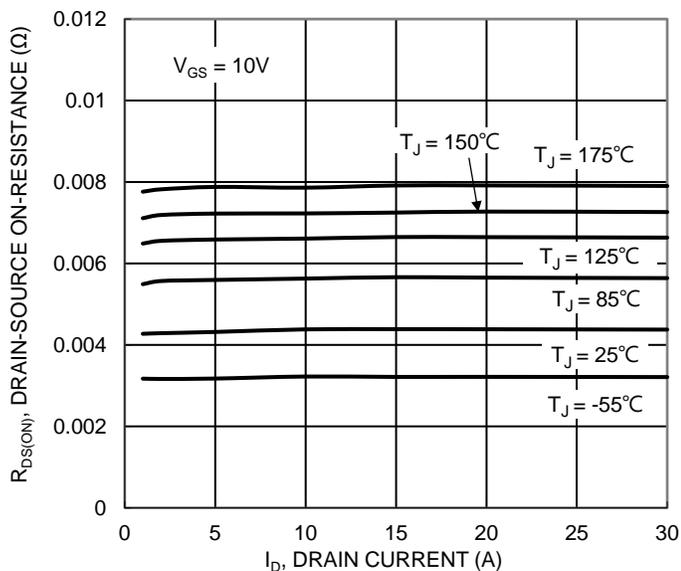


Fig. 5 Typical On-Resistance vs. Drain Current and Junction Temperature

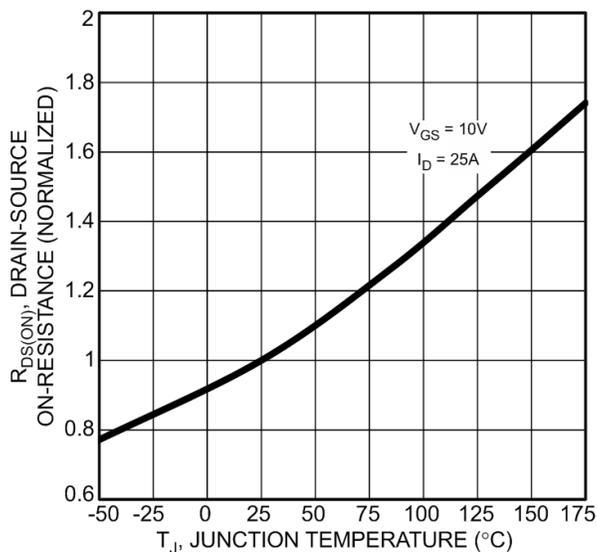


Fig. 6 On-Resistance Variation with Junction Temperature

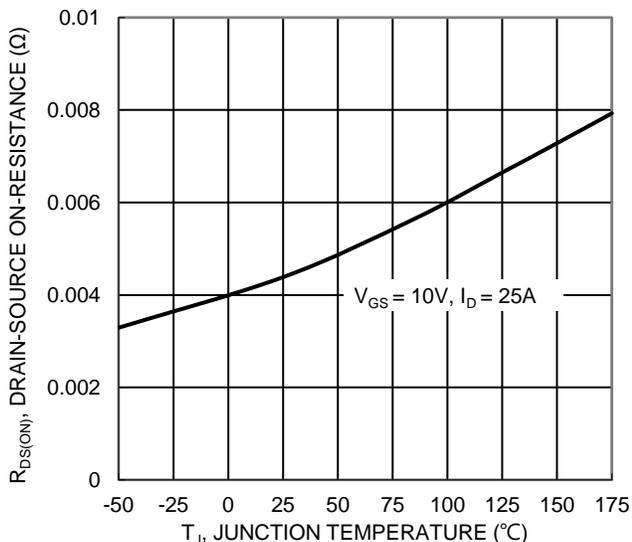


Fig. 7 On-Resistance Variation with Junction Temperature

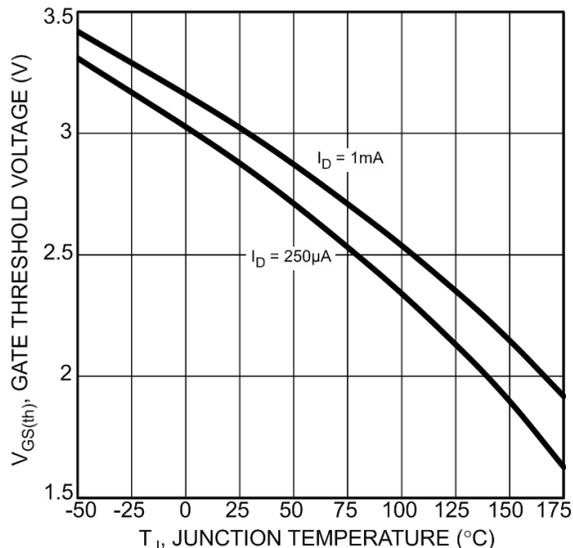


Fig. 8 Gate Threshold Variation vs. Junction Temperature

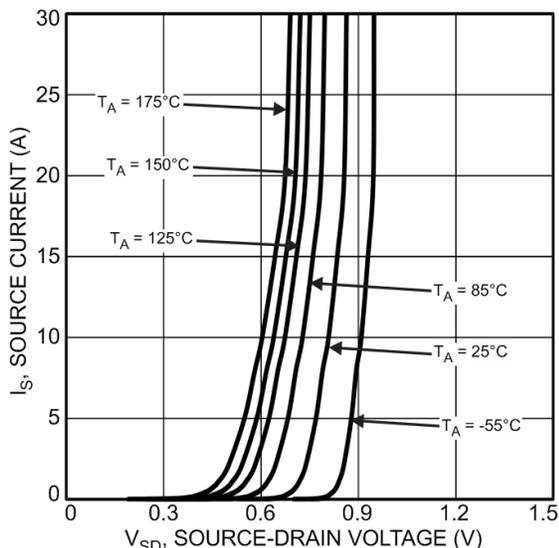


Fig. 9 Diode Forward Voltage vs. Current

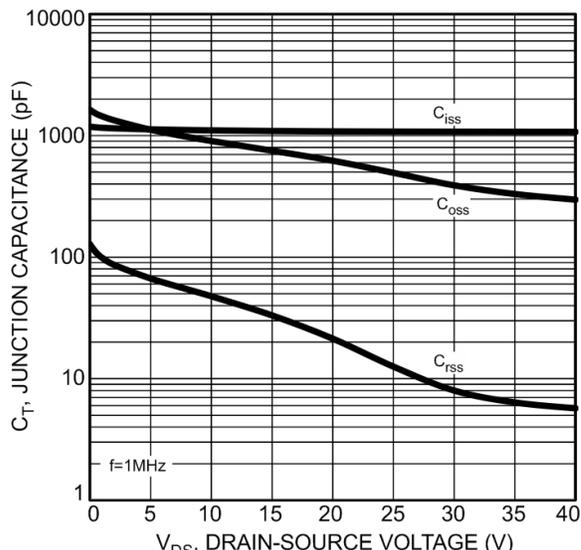


Fig. 10 Typical Junction Capacitance

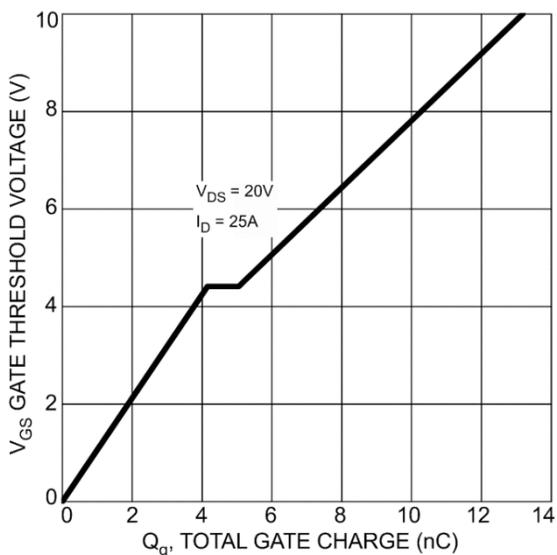


Fig. 11 Gate Charge

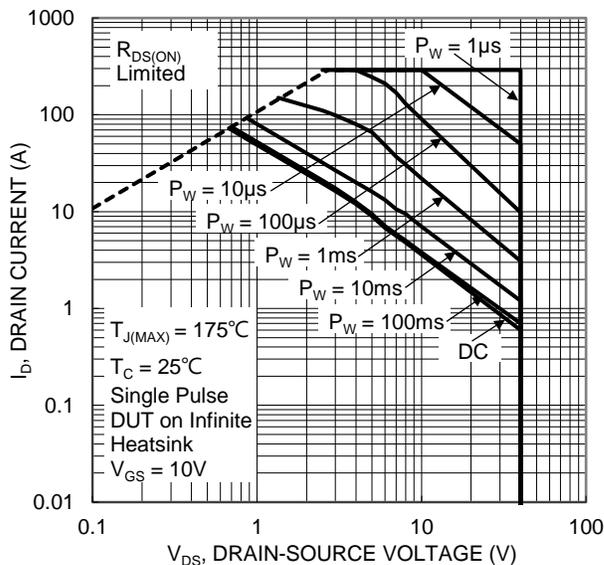


Fig. 12 SOA, Safe Operation Area

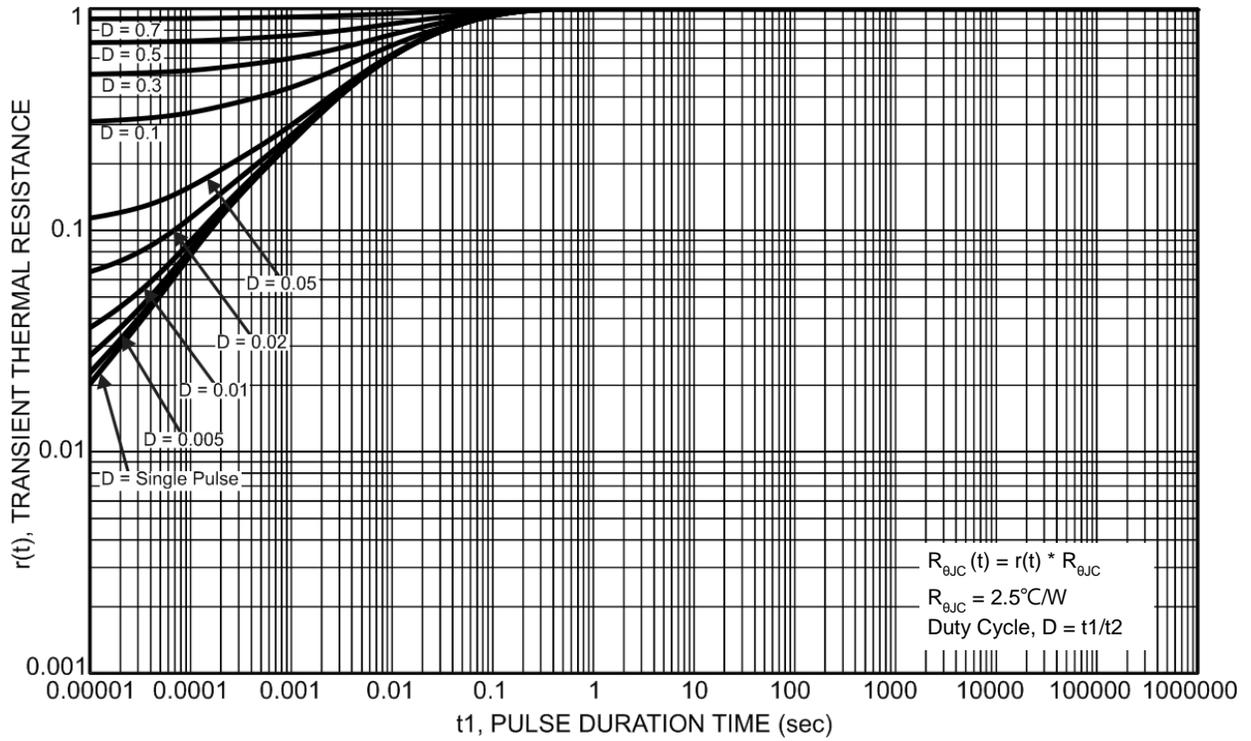
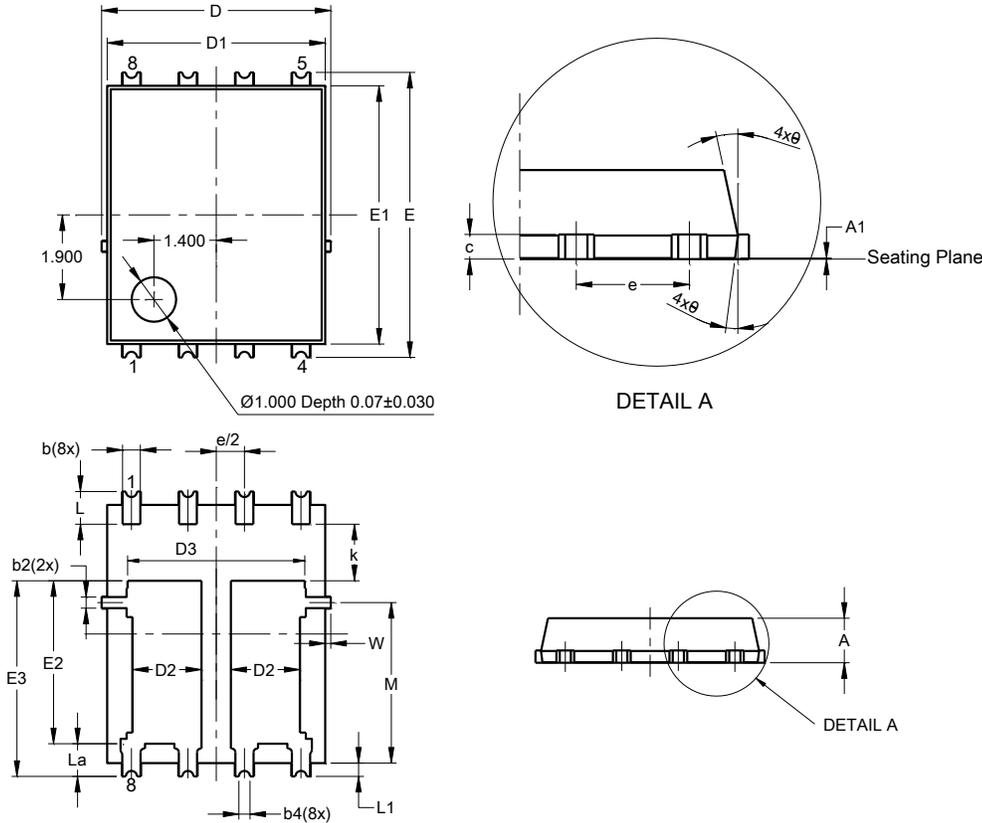


Fig. 13 Transient Thermal Resistance

### Package Outline Dimensions

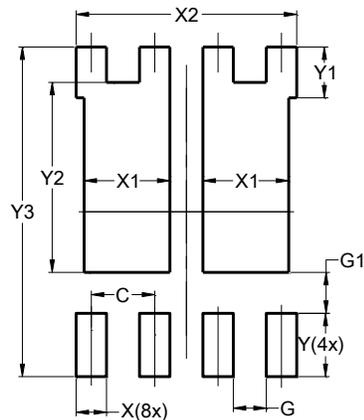
PowerDI5060-8/SWP (Type UXD)



PowerDI5060-8/SWP (Type UXD)			
Dim	Min	Max	Typ
A	0.90	1.10	1.00
A1	0.00	0.05	--
b	0.30	0.50	0.41
b2	0.20	0.35	0.25
b4	0.25REF		
c	0.230	0.330	0.277
D	5.15 BSC		
D1	4.70	5.10	4.90
D2	1.46	1.66	1.55
D3	3.78	4.18	3.98
E	6.40 BSC		
E1	5.60	6.00	5.80
E2	3.46	3.86	3.66
E2a	4.195	4.595	4.395
e	1.27BSC		
k	1.05	--	--
L	0.635	0.835	0.735
La	0.635	0.835	0.735
L1	0.200	0.400	0.300
M	3.205	4.005	3.605
W	0.025	0.225	0.125
θ	10°	12°	11°
θ1	6°	8°	7°
All Dimensions in mm			

### Suggested Pad Layout

PowerDI5060-8/SWP (Type UXD)



Dimensions	Value (in mm)
C	1.270
G	0.660
G1	0.820
X	0.610
X1	1.720
X2	4.420
Y	1.270
Y1	1.020
Y2	3.810
Y3	6.610